

H. Zhao, S. A. Vatavu, I. M. Caraman, P. A. Gasin, D. L. Morel and C. S. Ferekides, "The effect of Cu and annealing treatments on CdS/CdTe heterostructures studied with QE and photocurrent relaxation techniques," *2008 33rd IEEE Photovoltaic Specialists Conference*, San Diego, CA, USA, 2008, pp. 1-5, doi: 10.1109/PVSC.2008.4922556.

The photo-emf (photocurrent) decay at light impulses excitation (in longitudinal configuration) has been used to determine the lifetime of the non-equilibrium charge carriers recombining in different regions of the CdS/CdTe Cu containing heterojunction at different temperatures and biases. The photosensitivity spectral distributions have been investigated for samples with different technological variations.